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Date: 3/4/2007  
Time: 15:23:38**Inventor Name Search Result**

Your Search was:

Last Name = KURITA

First Name = KAZUNARI

Application#	Patent#	Status	Date Filed	Title	Inventor Name
*10531434	Not Issued <i>Applicants' Invention</i>	30	02/17/2006	Method for measuring point defect distribution of silicon single crystal ingot	KURITA, KAZUNARI
10576321	Not Issued	25	04/19/2006	Process for producing high-resistance silicon wafers and process for producing epitaxial wafers and soi wafers (as amended)	KURITA, KAZUNARI
*10784411	7074271 <i>Reviewed</i>	150	02/23/2004	METHOD OF IDENTIFYING DEFECT DISTRIBUTION IN SILICON SINGLE CRYSTAL INGOT	KURITA, KAZUNARI
11700492	Not Issued	19	01/01/0001	High frequency diode and method for producing same	KURITA, KAZUNARI

**Inventor Search Completed: No Records to Display.**

**Search Another: Inventor**

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## Inventor Name Search Result

Your Search was:

Last Name = FURUKAWA

First Name = JUN

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>06659755</u>	Not Issued	161	10/11/1984	ANTITUMOR AGENT AND METHOD FOR TREATING TUMOR USING THE SAME	FURUKAWA, JUN
<u>07559628</u>	Not Issued	166	07/30/1990	HIGH-STRENGTH, DAMAGE-RESISTANT RAIL	FURUKAWA, JUN
<u>07774819</u>	Not Issued	166	10/11/1991	ROLLING ROLLER AND ROLLING MILL	FURUKAWA, JUN
<u>07866129</u>	<u>5209792</u>	150	04/07/1992	HIGH-STRENGTH, DAMAGE-RESISTANT RAIL	FURUKAWA, JUN
<u>07873602</u>	<u>5166964</u>	150	04/21/1992	METHOD AND APPARATUS FOR MEASURING DENSITY	FURUKAWA, JUN
<u>07932564</u>	<u>5242766</u>	150	08/20/1992	HYDROGEN-OCCLUSION ELECTRODE	FURUKAWA, JUN
<u>07932568</u>	Not Issued	166	08/20/1992	METHOD OF MANUFACTURING A SEALED-TYPE NICKEL-HYDROGEN CELL	FURUKAWA, JUN
<u>07970656</u>	<u>5327762</u>	150	11/02/1992	ROLLING ROLLER AND ROLLING MILL	FURUKAWA, JUN
<u>08046846</u>	Not Issued	166	04/14/1993	SEALED-TYPE NICKEL/HYDROGEN ALKALINE STORAGE BATTERY	FURUKAWA, JUN
<u>08064866</u>	<u>5322527</u>	250	05/24/1993	METHOD OF MANUFACTURING SEALED-TYPE STORAGE BATTERIES USING HYDROGEN-OCCLUSION ELECTRODES	FURUKAWA, JUN
<u>08095257</u>	<u>5395712</u>	150	07/22/1993	PASTE-TYPE NICKEL ELECTRODE FOR AN ALKALINE STORAGE BATTERY AND AN ALKALINE STORAGE BATTERY CONTAINING THE	FURUKAWA, JUN

				ELECTRODE	
<u>08138382</u>	<u>5334226</u>	250	10/20/1993	METHOD OF MANUFACTURING A SEALED-TYPE NICKEL-HYDROGEN CELL	FURUKAWA, JUN
<u>08162773</u>	<u>5435055</u>	250	12/08/1993	METHOD OF MANUFACTURING A SEALED ALKALINE STORAGE BATTERY USING POSITIVE PASTE NICKEL ELECTRODES	FURUKAWA, JUN
<u>08173075</u>	<u>5441833</u>	150	12/27/1993	PASTE NICKEL ELECTRODE PLATE AND A STORAGE BATTERY INCLUDING AN ELECTROCONDUCTIVE MATERIAL	FURUKAWA, JUN
<u>08200464</u>	Not Issued	161	02/23/1994	SEALED-TYPE NICKEL/HYDROGEN ALKALINE STORAGE BATTERY	FURUKAWA, JUN
<u>08215476</u>	<u>5384210</u>	250	03/21/1994	HYDROGEN-OCCULSION ALLOY FOR THE ELECTRODES OF A SEALED-TYPE STORAGE BATTERY	FURUKAWA, JUN
<u>08217943</u>	<u>5466544</u>	150	03/25/1994	METHOD FOR MANUFACTURING A HYDROGEN-OCCLUSION-ALLOY ELECTRODE	FURUKAWA, JUN
<u>08293847</u>	<u>5496665</u>	150	08/22/1994	HYDROGEN-OCCLUSION-ALLOY ELECTRODE	FURUKAWA, JUN
<u>08314328</u>	<u>5542958</u>	150	09/28/1994	METHOD FOR MANUFACTURING A HYDROGEN ABSORBING ALLOY ELECTRODE	FURUKAWA, JUN
<u>08444862</u>	<u>5514497</u>	150	05/19/1995	PASTE NICKEL ELECTRODE PLATE AND A STORAGE BATTERY INCLUDING AN ELECTROCONDUCTIVE MATERIAL	FURUKAWA, JUN
<u>08709722</u>	<u>5775602</u>	250	09/09/1996	MANUFACTURING METHOD FOR A HYDROGEN-STORAGE-ALLOY POWDER FOR BATTERIES	FURUKAWA, JUN
<u>08785647</u>	Not Issued	161	01/17/1997	HIGH-STRENGTH, DAMAGE-RESISTANT RAIL HAVING HARDNESS DISTRIBUTION OF EXCELLENT DAMAGE-	FURUKAWA, JUN

				RESISTANCE AT ITS HEAD TOP PORTION	
<u>08863220</u>	<u>5876874</u>	250	05/27/1997	NICKEL ELECTRODE FOR SECONDARY BATTERY	FURUKAWA, JUN
<u>09231440</u>	<u>6361625</u>	250	01/14/1999	HIGH-STRENGTH, DAMAGE- RESISTANT RAIL HAVING HARDNESS DISTRIBUTION OF EXCELLENT DAMAGE- RESISTANCE AT ITS HEAD TOP PORTION	FURUKAWA, JUN
<u>09397202</u>	<u>6804827</u>	150	09/16/1999	TRANSMISSION SYSTEM AND METHOD SIGNAL ADJUSTING APPARATUS AND METHOD AND ROUTING APPARATUS	FURUKAWA, JUN
<u>09667885</u>	<u>6663708</u>	150	09/22/2000	SILICON WAFER, AND MANUFACTURING METHOD AND HEAT TREATMENT METHOD OF THE SAME	FURUKAWA, JUN
<u>09718659</u>	Not Issued	161	11/22/2000	Silicon wafer and method for manufacturing the same	FURUKAWA, JUN
<u>09796458</u>	<u>7035404</u>	150	03/02/2001	METHOD AND APPARATUS FOR SHUFFLE WITH PROOF, METHOD AND APPARATUS FOR SHUFFLE VERIFICATION, METHOD AND APPARATUS FOR GENERATING INPUT MESSAGE SEQUENCE AND PROGRAM FOR SAME	FURUKAWA, JUN
<u>09806550</u>	<u>6447600</u>	150	03/30/2001	DEFECT ELIMINATING METHOD OF SINGLE CRYSTAL BODY, AND SINGLE CRYSTAL BODY DEFECT- ELIMINATED BY SUCH METHOD	FURUKAWA, JUN
<u>09875146</u>	<u>6558483</u>	150	06/07/2001	CU PRECIPITATION STRENGTHENED STEEL	FURUKAWA, JUN
<u>10137407</u>	Not Issued	93	05/03/2002	CERTIFIED SHUFFLE- DECRYPTING SYSTEM, CERTIFIED SHUFFLE- DECRYPTING METHOD AND CERTIFIED SHUFFLE- DECRYPTION VERIFYING METHOD	FURUKAWA, JUN
<u>10164311</u>	<u>7039825</u>	150	06/07/2002	CLOCK REPRODUCING METHOD AND RECEIVING CLOCK PRODUCING APPARATUS ALLOWING FOR	FURUKAWA, JUN

				ABSORPTION OF TRANSMISSION CHANNEL JITTER	
<u>10212172</u>	<u>7003541</u>	150	08/06/2002	ZERO-KNOWLEDGE PROVING SYSTEM AND METHOD	FURUKAWA, JUN
<u>10521035</u>	Not Issued	95	08/02/2005	METHOD FOR MANUFACTURING SILICON SINGLE CRYSTAL	FURUKAWA, JUN
<u>*10531434</u>	Not Issued <i>Applicants' Invention</i>	30	02/17/2006	Method for measuring point defect distribution of silicon single crystal ingot	FURUKAWA, JUN
<u>10546645</u>	Not Issued	20	08/24/2005	Mixnet system	FURUKAWA, JUN
<u>10558790</u>	Not Issued	20	11/28/2005	Method of simulation with respect to density distribution and size distribution of void defect within single crystal and oxygen precipitation nucleus within single crystal	FURUKAWA, JUN
<u>10587308</u>	Not Issued	19	01/01/0001	Method and device for calculating a function from a large number of inputs	FURUKAWA, JUN
<u>10628690</u>	Not Issued	161	07/28/2003	Method of manufacturing silicon	FURUKAWA, JUN
<u>10718663</u>	Not Issued	25	11/24/2003	Weakly computational zero-knowledge proof and evaluation	FURUKAWA, JUN
<u>10754111</u>	Not Issued	71	01/08/2004	Lead-based alloy for lead-acid battery, substrate for lead-acid battery and lead-acid battery	FURUKAWA, JUN
<u>*10784411</u>	<u>7074271</u> <i>Review application of Rob Furukawa</i>	150	02/23/2004	METHOD OF IDENTIFYING DEFECT DISTRIBUTION IN SILICON SINGLE CRYSTAL INGOT	FURUKAWA, JUN
<u>10951807</u>	Not Issued	30	09/29/2004	Pulse based communication system	FURUKAWA, JUN
<u>10995478</u>	Not Issued	30	11/24/2004	Cryptographic communication system	FURUKAWA, JUN
<u>11030488</u>	Not Issued	61	01/05/2005	Lead-based alloy for lead-acid battery, grid for lead-acid battery and lead-acid battery	FURUKAWA, JUN
<u>11130228</u>	Not Issued	30	05/17/2005	Impulse-based communication system	FURUKAWA, JUN
<u>11382121</u>	Not Issued	25	05/08/2006	Method For Manufacturing Nitrogen-Doped Silicon Single Crystal	FURUKAWA, JUN

<a href="#">11553854</a>	Not Issued	25	10/27/2006	Method for manufacturing silicon single crystal	FURUKAWA, JUN
<a href="#">06420843</a>	<a href="#">4475492</a>	250	09/21/1982	SYSTEM FOR FORCEFULLY IGNITING SPRAYED FUEL OF A DIESEL ENGINE DURING ENGINE STARTING	FURUKAWA, JUNICHI
<a href="#">06442906</a>	<a href="#">4457285</a>	250	11/19/1982	SUSTAINED ARC IGNITION SYSTEM FOR AN INTERNAL COMBUSTION ENGINE	FURUKAWA, JUNICHI

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10/531434

Examiner: HITESHEW, FELISA


Inventor: KURITA, KAZUNARI, et al

Status: 30 - DOCKETED NEW CASE - READY FOR EXAMINATION

Title: METHOD FOR MEASURING POINT DEFECT DISTRIBUTION OF SILICON SINGLE CRYSTAL INGOT

GAU: 1722  
Classification: 117/013.000

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10/531434

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	13	FOR	Foreign Reference	04/15/2005	38	
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